

February 2008

FDMC4435BZ

P-Channel Power Trench[®] MOSFET -30V, -18A, 20.0m Ω

Features

- Max $r_{DS(on)} = 20.0 \text{m}\Omega$ at $V_{GS} = -10 \text{V}$, $I_D = -8.5 \text{A}$
- Max $r_{DS(on)} = 37.0 \text{m}\Omega$ at $V_{GS} = -4.5 \text{V}$, $I_D = -6.3 \text{A}$
- Extended V_{GSS} range (-25V) for battery applications
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability
- HBM ESD protection level >7kV typical (Note 4)
- 100% UIL Tested
- Termination is Lead-free and RoHS Compliant

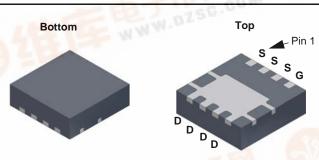
General Description

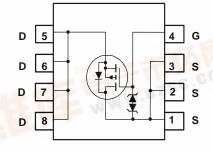
This P-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance. This devie is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.

Applications

- High side in DC DC Buck Converters
- Notebook battery power management
- Load switch in Notebook







Power 33

MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V _{DS}	Drain to Source Voltage			-30	V
V _{GS}	Gate to Source Voltage			±25	V
	Drain Current -Continuous (Package limited)	T _C = 25°C	1	-18	601
I _D	-Continuous (Silicon limited) T _C = 25°C			-31	
	-Continuous	$T_A = 25^{\circ}C$	(Note 1a)	-8.5	Α
	-Pulsed	The Table	14.1-	-50	
E _{AS}	Single Pulse Avalanche Energy	EA\((()) =	(Note 3)	24	mJ
В	Power Dissipation	$T_C = 25^{\circ}C$		31	W
P_{D}	Power Dissipation	T _A = 25°C	(Note 1a)	2.3	VV
T _J , T _{STG}	Operating and Storage Junction Temperature R	ange		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	4	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	53	C/VV

Package Marking and Ordering Information

ppevice Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC4435BZ	FDMC4435BZ	Power 33	13"	12mm	3000 units

Electrical Characteristics T_J = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu A$, referenced to 25°C		22		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24V,$ $V_{GS} = 0V,$ $T_{J} = 125^{\circ}C$			-1 -100	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$			±10	μΑ

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-1.0	-1.9	-3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = -250μA, referenced to 25°C		-5.3		mV/°C
		$V_{GS} = -10V, I_D = -8.5A$		14.6	20.0	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = -4.5V, I_D = -6.3A$		23.1	37.0	mΩ
, ,		$V_{GS} = -10V, I_D = -8.5A, T_J = 125^{\circ}C$		20.7	28.0	
g _{FS}	Forward Transconductance	$V_{DD} = -5V, I_{D} = -8.5A$		24		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45V V 6V	1540	2045	pF
C _{oss}	Output Capacitance	$V_{DS} = -15V, V_{GS} = 0V,$ $f = 1MHz$	295	395	pF
C _{rss}	Reverse Transfer Capacitance	1 – 111112	260	385	pF
R_g	Gate Resistance	f = 1MHz	5.1		Ω

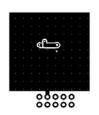
Switching Characteristics

t _{d(on)}	Turn-On Delay Time		10	20	ns
t _r	Rise Time	V_{DD} = -15V, I_D = -8.5A, V_{GS} = -10V, R_{GEN} = 6Ω	6	12	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = -10V$, $K_{GEN} = 0.22$	34	55	ns
t _f	Fall Time		20	36	ns
Qg	Total Gate Charge	V _{GS} =0V to -10V	33	46	nC
Qg	Total Gate Charge	$V_{GS} = 0V \text{ to -4.5V} V_{DD} = -15V,$	17	24	nC
Q _{gs}	Gate to Source Charge	I _D = -8.5A	5		nC
Q_{gd}	Gate to Drain "Miller" Charge		9		nC

Drain-Source Diode Characteristics

V		$V_{GS} = 0V, I_{S} = -8.5A$ (Note 2)	0.92	1.5	\/
V SD		$V_{GS} = 0V, I_S = -1.9A$ (Note 2)	0.75	1.2	V
t _{rr}	Reverse Recovery Time	I _E = -8.5A, di/dt = 100A/μs	22		ns
Q _{rr}	Reverse Recovery Charge	T _F = -8.5A, αl/αt = 100A/μs	11		nC

^{1.} R_{9,JA} is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{9,JC} is guaranteed by design while R_{9CA} is determined by the user's board design.



a. 53°C/W when mounted on a 1 in² pad of 2 oz copper



b. 125°C/W when mounted on a minimum pad of 2 oz copper

- 2: Pulse Test: Pulse Width < $300\mu s$, Duty cycle < 2.0%.
- 3. Starting T_J = 25°C, L = 1mH, $I_{\mbox{\scriptsize AS}}$ = -7A, $V_{\mbox{\scriptsize DD}}$ = -27V, $V_{\mbox{\scriptsize GS}}$ = -10V.
- 4. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

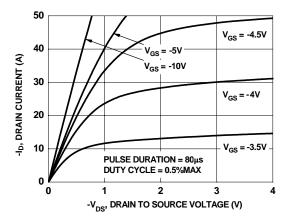


Figure 1. On-Region Characteristics

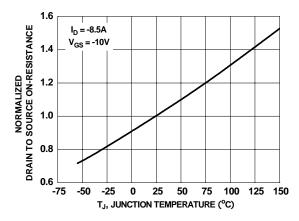


Figure 3. Normalized On-Resistance vs Junction Temperature

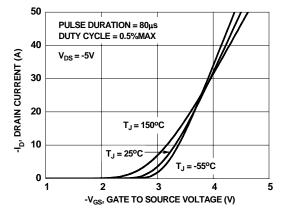


Figure 5. Transfer Characteristics

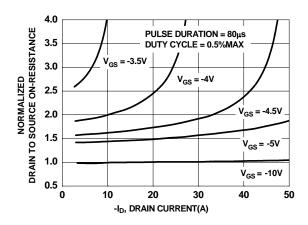


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

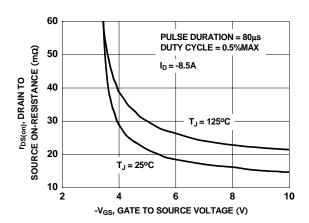


Figure 4. On-Resistance vs Gate to Source Voltage

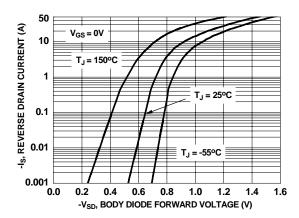


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

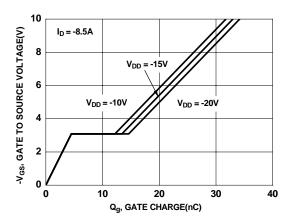


Figure 7. Gate Charge Characteristics

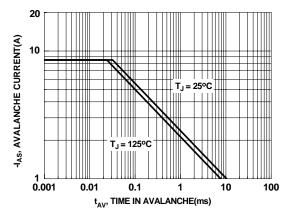


Figure 9. Unclamped Inductive Switching Capability

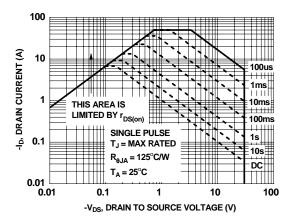


Figure 11. Forward Bias Safe Operating Area

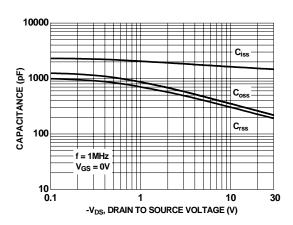


Figure 8. Capacitance vs Drain to Source Voltage

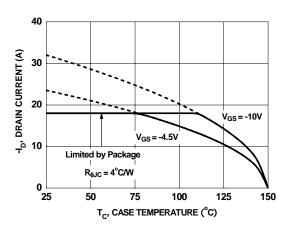


Figure 10. Maximum Continuous Drain Current vs Case Temperature

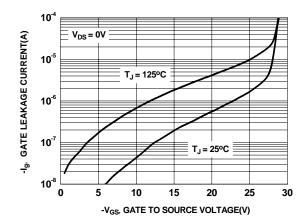


Figure 12. Igss vs Vgss

Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

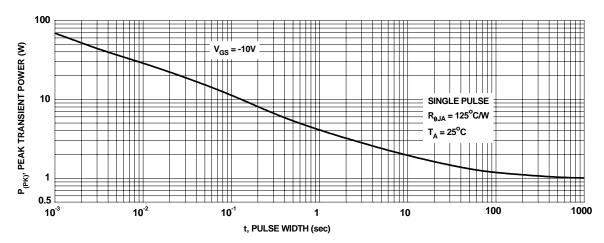


Figure 13. Single Pulse Maximum Power Dissipation

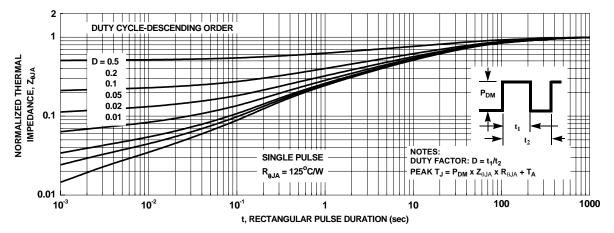
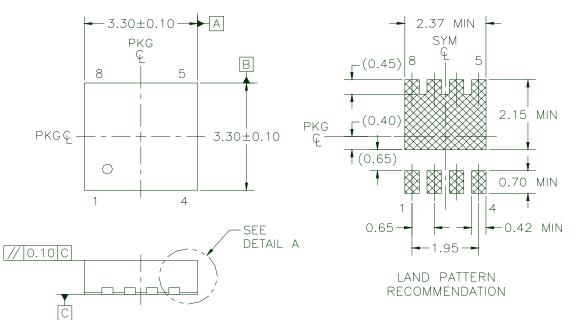
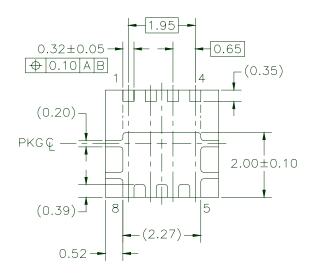
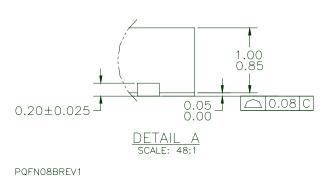


Figure 14. Transient Thermal Response Curve

Dimensional Outline and Pad Layout







FDMC4435BZ Rev.C

NOTES: UNLESS OTHERWISE SPECIFIED

- PACKAGE STANDARD REFERENCE: JEDEC MO229, ISSUE B, VEEC, DATED NOVEMBER 2001.
- ALL DIMENSIONS ARE IN MILLIMETERS.
 DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH.
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

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